Se	arcn	Notes	

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/730,817	OWEN ET AL.	
Examiner	Art Unit	
Insun Kang	2193	

	SEAR	CHED	-
Class	Subclass	Date	Examiner
717	106,114	3/31/2007	IK
717	116,118	3/31/2007	IK
717	135-167	3/31/2007	IK
	-		
	•		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			· ·

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
east/NPL	3/31/2007	IK
	·	
classification search (limited text)	3/31/2007	ΙK
double patenting search	3/31/2007	ΙK
	1	
	•	
	 	· ·